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# 256-Kbit (32K × 8) Automotive-E Serial (I<sup>2</sup>C) F-RAM

## Features

- 256-Kbit ferroelectric random access memory (F-RAM) logically organized as 32K × 8
  - High-endurance 10 trillion (10<sup>13</sup>) read/writes
  - 121-year data retention (See [Data Retention and Endurance on page 12](#))
  - NoDelay™ writes
  - Advanced high-reliability ferroelectric process
- Fast two-wire serial interface (I<sup>2</sup>C)
  - Up to 3.4-MHz frequency<sup>[1]</sup>
  - Direct hardware replacement for serial EEPROM
  - Supports legacy timings for 100 kHz and 400 kHz
- Device ID
  - Manufacturer ID and Product ID
- Low power consumption
  - 500-μA active current at 100 kHz
  - 500-μA standby current
  - 12-μA sleep mode current
- Low-voltage operation: V<sub>DD</sub> = 2.0 V to 3.6 V
- Automotive-E temperature: -40 °C to +125 °C
- 8-pin small outline integrated circuit (SOIC) package
- AEC Q100 Grade 1 compliant
- Restriction of hazardous substances (RoHS) compliant

## Functional Description

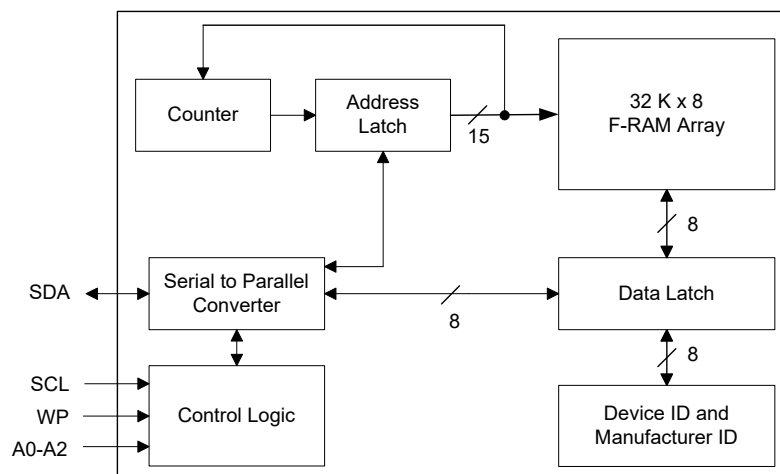
The CY15B256J is a 256-Kbit nonvolatile memory employing an advanced ferroelectric process. An F-RAM is nonvolatile and performs reads and writes similar to a RAM. It provides reliable data retention for 121 years while eliminating the complexities, overhead, and system-level reliability problems caused by EEPROM and other nonvolatile memories.

Unlike EEPROM, the CY15B256J performs write operations at bus speed. No write delays are incurred. Data is written to the memory array immediately after each byte is successfully transferred to the device. The next bus cycle can commence without the need for data polling. In addition, the product offers substantial write endurance compared with other nonvolatile memories. F-RAM also exhibits much lower power during writes than EEPROM because write operations do not require an internally elevated power supply voltage for write circuits. The CY15B256J is capable of supporting 10<sup>13</sup> read/write cycles, or 10 million times more write cycles than EEPROM.

These capabilities make the CY15B256J ideal for nonvolatile memory applications, requiring frequent or rapid writes. Examples range from data logging, where the number of write cycles may be critical, to demanding industrial controls where the long write time of EEPROM can cause data loss. The combination of features allows more frequent data writing with less overhead for the system.

The CY15B256J provides substantial benefits to users of serial EEPROM as a hardware drop-in replacement. The device incorporates a read-only Device ID that allows the host to determine the manufacturer, product density, and product revision. The device specifications are guaranteed over an Automotive-E temperature range of -40 °C to +125 °C.

## Logic Block Diagram



### Note

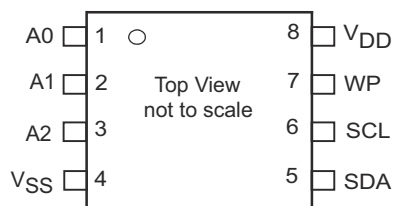
1. The CY15B256J does not meet the NXP I<sup>2</sup>C specification in the Fast-mode Plus (Fm+, 1 MHz) for I<sub>OL</sub> and in the High Speed Mode (Hs-mode, 3.4 MHz) for V<sub>hys</sub>. Refer to [DC Electrical Characteristics on page 11](#) for more details.

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## Pinout

**Figure 1. 8-pin SOIC Pinout**



## Pin Definitions

| Pin Name | I/O Type     | Description                                                                                                                                                                                                                                                                                                                                                |
|----------|--------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| A0–A2    | Input        | <b>Device Select Address 0–2.</b> These pins are used to select one of up to eight devices of the same type on the same two-wire bus. To select the device, the address value on the three pins must match the corresponding bits contained in the slave address. The address pins are pulled down internally.                                             |
| SDA      | Input/Output | <b>Serial Data Address.</b> This is a bidirectional pin for the two-wire interface. It is open-drain and is intended to be wire-AND'd with other devices on the two-wire bus. The input buffer incorporates a Schmitt trigger for noise immunity and the output driver includes slope control for falling edges. An external pull-up resistor is required. |
| SCL      | Input        | <b>Serial Clock.</b> The serial clock pin for the two-wire interface. Data is clocked out of the part on the falling edge, and into the device on the rising edge. The SCL input also incorporates a Schmitt trigger input for noise immunity.                                                                                                             |
| WP       | Input        | <b>Write Protect.</b> When tied to $V_{DD}$ , addresses in the entire memory map will be write-protected. When WP is connected to ground, all addresses are write enabled. This pin is pulled down internally.                                                                                                                                             |
| $V_{SS}$ | Power supply | Ground for the device. Must be connected to the ground of the system.                                                                                                                                                                                                                                                                                      |
| $V_{DD}$ | Power supply | Power supply input to the device.                                                                                                                                                                                                                                                                                                                          |

## Functional Overview

The CY15B256J is a serial F-RAM memory. The memory array is logically organized as  $32,768 \times 8$  bits and is accessed using a two-wire (I<sup>2</sup>C) interface. The functional operation of the F-RAM is similar to serial EEPROM. The major difference between the CY15B256J and a serial EEPROM with the same pinout is the F-RAM's superior write performance, high endurance, and low power consumption.

## Memory Architecture

When accessing the CY15B256J, the user addresses 32K locations of eight data bits each. These eight data bits are shifted in or out serially. The addresses are accessed using the two-wire protocol, which includes a slave address (to distinguish other non-memory devices) and a two-byte address. The upper MSB bit of the address range is 'don't care' value. The complete address of 15 bits specifies each byte address uniquely.

The access time for the memory operation is essentially zero, beyond the time needed for the serial protocol. That is, the memory is read or written at the speed of the two-wire bus. Unlike a serial EEPROM, it is not necessary to poll the device for a ready condition because writes occur at bus speed. By the time a new bus transaction can be shifted into the device, a write operation is complete. This is explained in more detail in [Memory Operation on page 7](#).

## Two-wire Interface

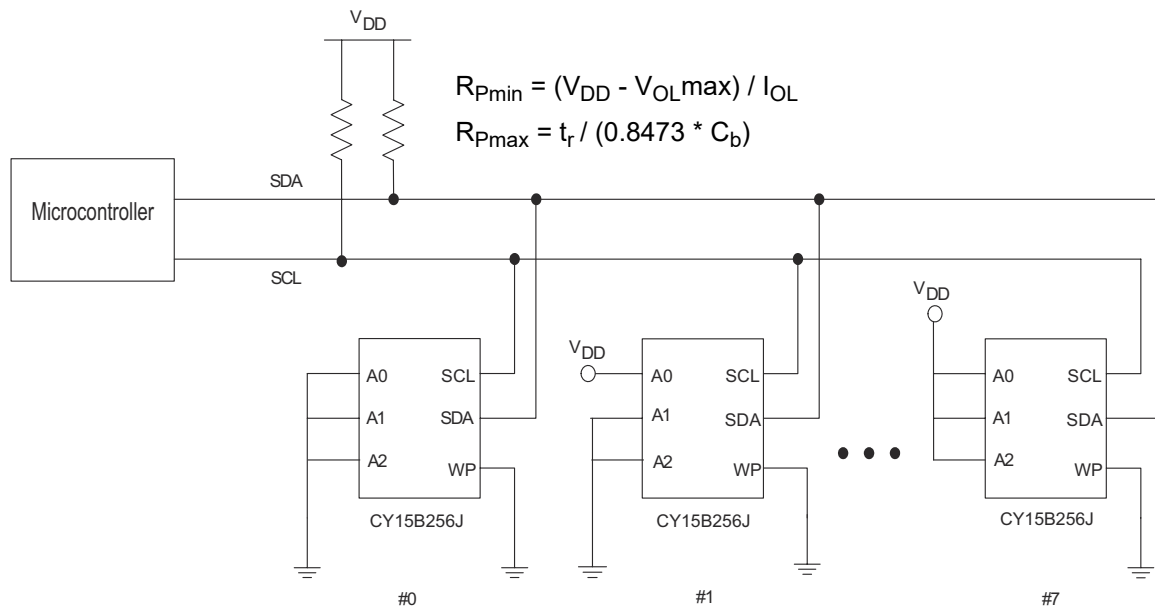
The CY15B256J employs a bidirectional two-wire bus protocol using few pins or board space. [Figure 2](#) illustrates a typical system configuration using the CY15B256J in a microcontroller-based system. The two-wire bus is familiar to many users but is described in this section.

By convention, any device that is sending data to the bus is the transmitter while the target device for this data is the receiver. The device that is controlling the bus is the master. The master is responsible for generating the clock signal for all operations. Any device on the bus that is being controlled is a slave. The CY15B256J is always a slave device.

The bus protocol is controlled by transition states in the SDA and SCL signals. There are four conditions including START, STOP, data bit, or acknowledge. [Figure 3 on page 5](#) and [Figure 4 on page 5](#) illustrate the signal conditions that specify the four states. Detailed timing diagrams are shown in the electrical specifications section.

The CY15B256J does not meet the NXP I<sup>2</sup>C specification in the Fast-mode Plus (Fm+, 1 MHz) for  $I_{OL}$  and in the High Speed Mode (Hs-mode, 3.4 MHz) for  $V_{hys}$ . Refer to [DC Electrical Characteristics on page 11](#) for more details.

**Figure 2. System Configuration using Serial (I<sup>2</sup>C) F-RAM**



### STOP Condition (P)

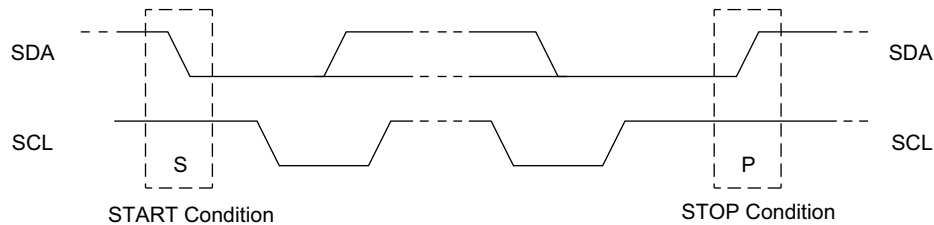
A STOP condition is indicated when the bus master drives SDA from low to HIGH while the SCL signal is HIGH. All operations using the CY15B256J should end with a STOP condition. If an operation is in progress when a STOP is asserted, the operation will be aborted. The master must have control of the SDA (not a memory read) to assert a STOP condition.

### START Condition (S)

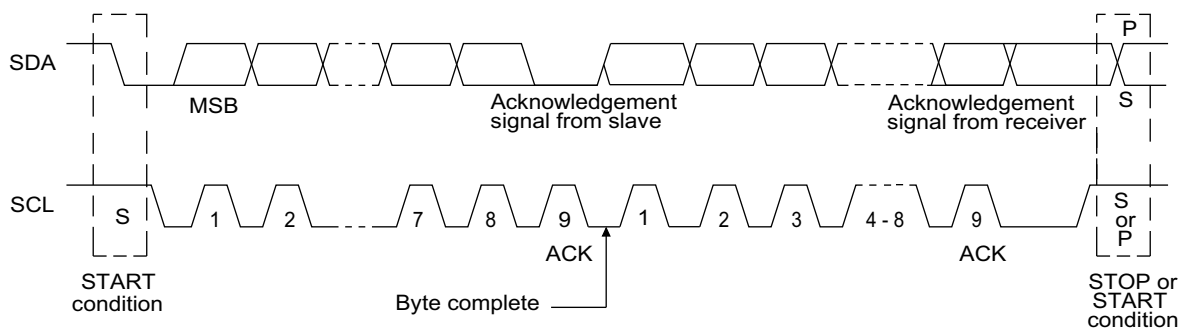
A START condition is indicated when the bus master drives SDA from HIGH to LOW while the SCL signal is HIGH. All commands should be preceded by a START condition. An operation in progress can be aborted by asserting a START condition at any time. Aborting an operation using the START condition will ready the CY15B256J for a new operation.

If the power supply drops below the specified  $V_{DD}$  minimum during operation, the system should issue a START condition prior to performing another operation.

**Figure 3. START and STOP Conditions**



**Figure 4. Data Transfer on the I<sup>2</sup>C Bus**



### Data/Address Transfer

All data transfers (including addresses) take place while the SCL signal is HIGH. Except under the three conditions described above, the SDA signal should not change while SCL is HIGH.

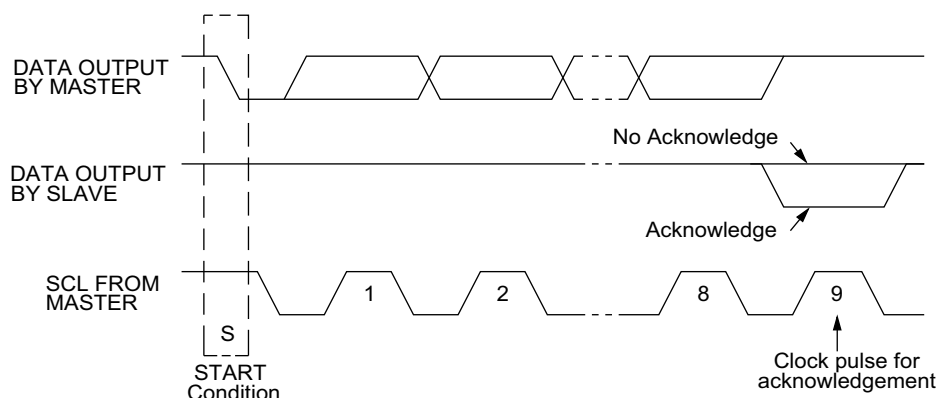
### Acknowledge/No-acknowledge

The acknowledge takes place after the 8th data bit has been transferred in any transaction. During this state the transmitter should release the SDA bus to allow the receiver to drive it. The receiver drives the SDA signal LOW to acknowledge receipt of the byte. If the receiver does not drive SDA LOW, the condition is a no-acknowledge and the operation is aborted.

The receiver will fail to acknowledge for two distinct reasons, the first being that a byte transfer fails. In this case, the no-acknowledge ceases the current operation so that the part can be addressed again. This allows the last byte to be recovered in the event of a communication error.

The second and most common reason is that, the receiver does not acknowledge to deliberately end an operation. For example, during a read operation, the CY15B256J will continue to place data on the bus as long as the receiver sends acknowledges (and clocks). When a read operation is complete and no more data is needed, the receiver must not acknowledge the last byte. If the receiver acknowledges the last byte, this causes the CY15B256J to attempt to drive the bus on the next clock while the master is sending a new command such as STOP.

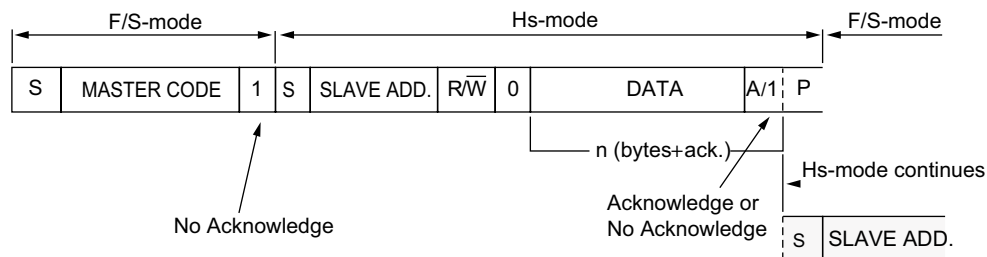
**Figure 5. Acknowledge on the I<sup>2</sup>C Bus**



## High Speed Mode (Hs-Mode)

The CY15B256J supports a 3.4-MHz high-speed mode. A master code (00001XXXb) must be issued to place the device into the high-speed mode. Communication between master and slave will then be enabled for speeds up to 3.4 MHz. A STOP condition will exit Hs-mode. Single- and multiple-byte reads and writes are supported.

**Figure 6. Data Transfer Format in Hs-Mode**

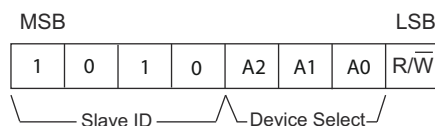


## Slave Device Address

The first byte that the CY15B256J expects after a START condition is the slave address. As shown in Figure 7, the slave address contains the device type or slave ID, the device select address bits, and a bit that specifies if the transaction is a read or a write.

Bits 7–4 are the device type (slave ID) and should be set to 1010b for the CY15B256J. These bits allow other function types to reside on the two-wire bus within an identical address range. Bits 3–1 are the device select address bits. They must match the corresponding value on the external address pins to select the device. Up to eight CY15B256J devices can reside on the same two-wire bus by assigning a different address to each. Bit 0 is the read/write bit (R/W). R/W = '1' indicates a read operation and R/W = '0' indicates a write operation.

**Figure 7. Memory Slave Device Address**



## Addressing Overview

After the CY15B256J (as receiver) acknowledges the slave address, the master can place the memory address on the bus for a write operation. The address requires two bytes. The complete 15-bit address is latched internally. Each access causes the latched address value to be incremented automatically. The current address is the value that is held in the latch; either a newly written value or the address following the last access. The current address will be held for as long as power remains or until a new value is written. Reads always use the current address. A random read address can be loaded by beginning a write operation as explained below.

After transmission of each data byte, just prior to the acknowledge, the CY15B256J increments the internal address latch. This allows the next sequential byte to be accessed with no additional addressing. After the last address (7FFFh) is reached, the address latch will roll over to 0000h. There is no limit to the number of bytes that can be accessed with a single read or write operation.

## Data Transfer

After the address bytes have been transmitted, data transfer between the bus master and the CY15B256J can begin. For a read operation the CY15B256J will place 8 data bits on the bus then wait for an acknowledge from the master. If the acknowledge occurs, the CY15B256J will transfer the next sequential byte. If the acknowledge is not sent, the CY15B256J will end the read operation. For a write operation, the CY15B256J will accept 8 data bits from the master then sends an acknowledge. All data transfer occurs MSB (most significant bit) first.

## Memory Operation

The CY15B256J is designed to operate in a manner very similar to other two-wire interface memory products. The major differences result from the higher performance write capability of F-RAM technology. These improvements result in some differences between the CY15B256J and a similar configuration EEPROM during writes. The complete operation for both writes and reads is explained below.

### Write Operation

All writes begin with a slave address, then a memory address. The bus master indicates a write operation by setting the LSB of the slave address (R/W bit) to a '0'. After addressing, the bus master sends each byte of data to the memory and the memory generates an acknowledge condition. Any number of sequential bytes may be written. If the end of the address range is reached internally, the address counter will wrap from 7FFFh to 0000h.

Unlike other nonvolatile memory technologies, there is no effective write delay with F-RAM. Since the read and write access times of the underlying memory are the same, the user experiences no delay through the bus. The entire memory cycle occurs in less time than a single bus clock. Therefore, any

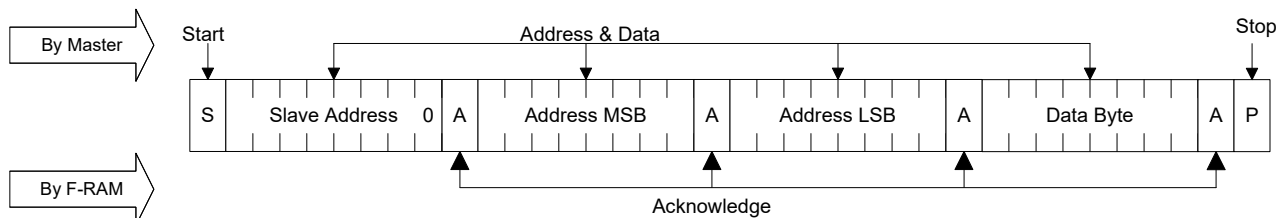
operation including read or write can occur immediately following a write. Acknowledge polling, a technique used with EEPROMs to determine if a write is complete is unnecessary and will always return a ready condition.

Internally, an actual memory write occurs after the 8th data bit is transferred. It will be complete before the acknowledge is sent. Therefore, if the user desires to abort a write without altering the memory contents, this should be done using START or STOP condition prior to the 8th data bit. The CY15B256J uses no page buffering.

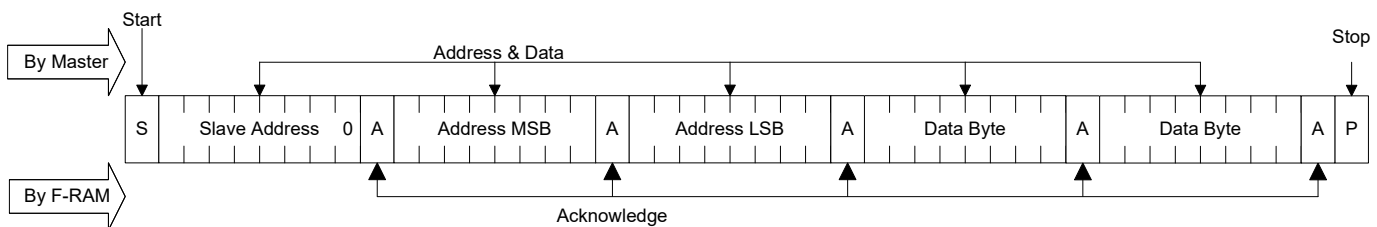
The memory array can be write-protected using the WP pin. Setting the WP pin to a HIGH condition ( $V_{DD}$ ) will write-protect all addresses. The CY15B256J will not acknowledge data bytes that are written to protected addresses. In addition, the address counter will not increment if writes are attempted to these addresses. Setting WP to a LOW state ( $V_{SS}$ ) will disable the write protect. WP is pulled down internally.

Figure 8 and Figure 9 below illustrate a single-byte and multiple-byte write cycles in Fast-mode Plus (Fm+). Figure 10 below illustrate a single-byte write cycles in Hs mode.

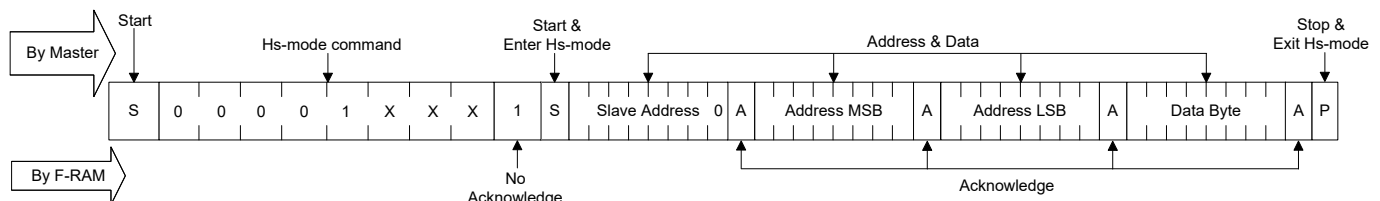
**Figure 8. Single-Byte Write**



**Figure 9. Multi-Byte Write**



**Figure 10. Hs-Mode Byte Write**





## Read Operation

There are two basic types of read operations. They are current address read and selective address read. In a current address read, the CY15B256J uses the internal address latch to supply the address. In a selective read, the user performs a procedure to set the address to a specific value.

### Current Address & Sequential Read

As mentioned above the CY15B256J uses an internal latch to supply the address for a read operation. A current address read uses the existing value in the address latch as a starting place for the read operation. The system reads from the address immediately following that of the last operation.

To perform a current address read, the bus master supplies a slave address with the LSB set to a '1'. This indicates that a read operation is requested. After receiving the complete slave address, the CY15B256J will begin shifting out data from the current address on the next clock. The current address is the value held in the internal address latch.

Beginning with the current address, the bus master can read any number of bytes. Thus, a sequential read is simply a current

address read with multiple byte transfers. After each byte the internal address counter will be incremented.

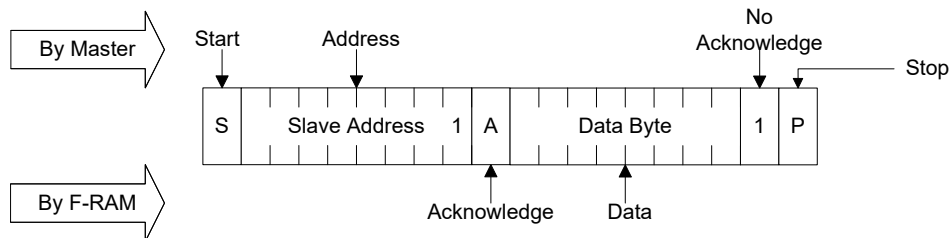
**Note** Each time the bus master acknowledges a byte, this indicates that the CY15B256J should read out the next sequential byte.

There are four ways to properly terminate a read operation. Failing to properly terminate the read will most likely create a bus contention as the CY15B256J attempts to read out additional data onto the bus. The four valid methods are:

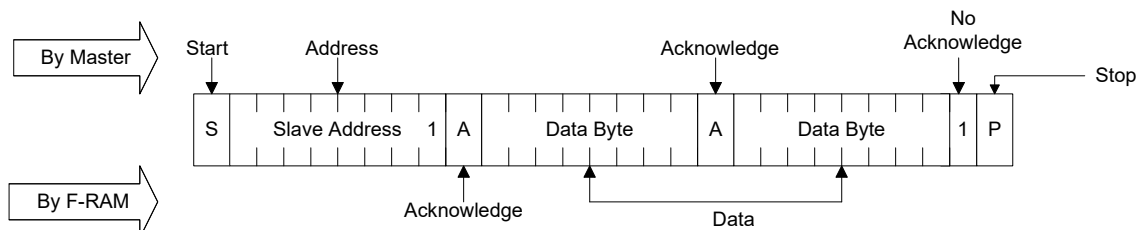
1. The bus master issues a no-acknowledge in the 9th clock cycle and a STOP in the 10th clock cycle. This is illustrated in the diagrams below. This is preferred.
2. The bus master issues a no-acknowledge in the 9th clock cycle and a START in the 10th.
3. The bus master issues a STOP in the 9th clock cycle.
4. The bus master issues a START in the 9th clock cycle.

If the internal address reaches 7FFFh, it will wrap around to 0000h on the next read cycle. [Figure 11](#) and [Figure 12](#) below show the proper operation for current address reads.

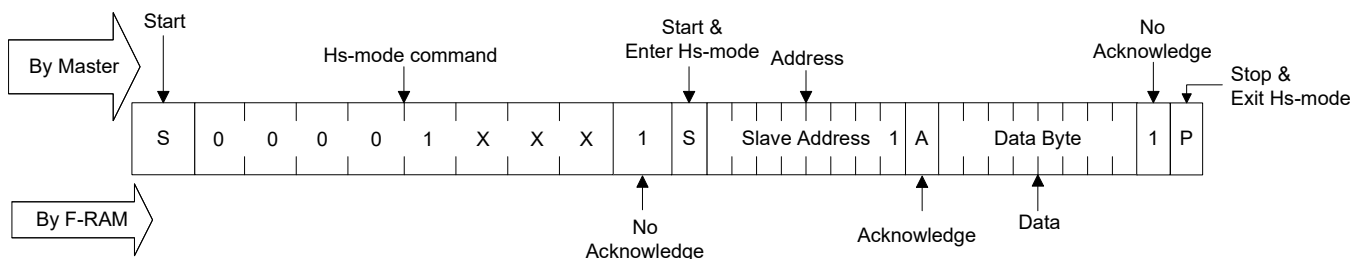
**Figure 11. Current Address Read**



**Figure 12. Sequential Read**



**Figure 13. Hs-Mode Current Address Read**

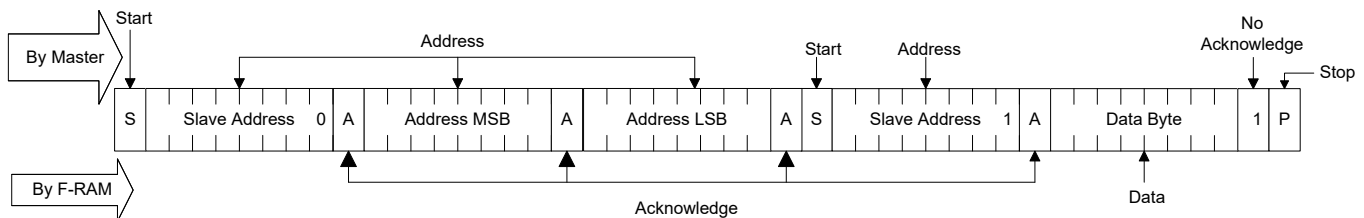


### Selective (Random) Read

There is a simple technique that allows a user to select a random address location as the starting point for a read operation. This involves using the first three bytes of a write operation to set the internal address followed by subsequent read operations.

To perform a selective read, the bus master sends out the slave address with the LSB (R/W) set to 0. This specifies a write operation. According to the write protocol, the bus master then sends the address bytes that are loaded into the internal address latch. After the CY15B256J acknowledges the address, the bus master issues a START condition. This simultaneously aborts the write operation and allows the read command to be issued with the slave address LSB set to a '1'. The operation is now a current address read.

**Figure 14. Selective (Random) Read**



### Sleep Mode

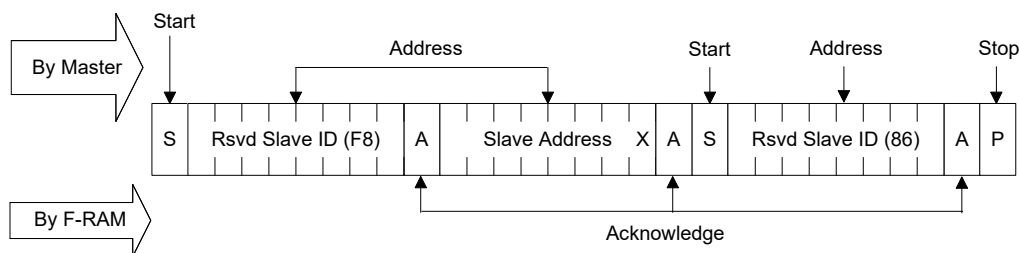
A low-power mode called Sleep Mode is implemented on the CY15B256J device. The device will enter this low power state when the Sleep command 86h is clocked-in. Sleep Mode entry can be entered as follows:

1. The master sends a START command.
2. The master sends Reserved Slave ID 0xF8.
3. The CY15B256J sends an ACK.
4. The master sends the I<sup>2</sup>C-bus slave address of the slave device it needs to identify. The last bit is a 'Don't care' value (R/W bit). Only one device must acknowledge this byte (the one that has the I<sup>2</sup>C-bus slave address).
5. The CY15B256J sends an ACK.

6. The master sends a Re-START command.
7. The master sends Reserved Slave ID 0x86.
8. The CY15B256J sends an ACK.
9. The master sends STOP to ensure the device enters sleep mode.

Once in sleep mode, the device draws  $I_{ZZ}$  current, but the device continues to monitor the I<sup>2</sup>C pins. Once the master sends a Slave Address that the CY15B256J identifies, it will "wake up" and be ready for normal operation within  $t_{REC}$  (400  $\mu$ s max.). As an alternative method of determining when the device is ready, the master can send read or write commands and look for an ACK. While the device is waking up, it will NACK the master until it is ready.

**Figure 15. Sleep Mode Entry**



## Device ID

The CY15B256J device incorporates a means of identifying the device by providing three bytes of data, which are manufacturer, product ID, and die revision. The Device ID is read-only. It can be accessed as follows:

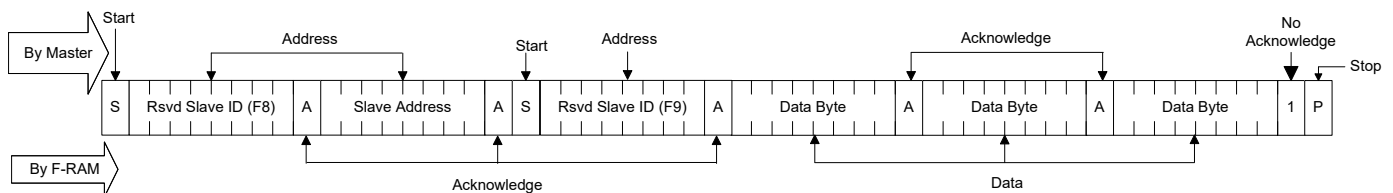
1. The master sends a START command.
  2. The master sends Reserved Slave ID 0xF8
  3. The CY15B256J sends an ACK.
  4. The master sends the I<sup>2</sup>C-bus slave address of the slave device it needs to identify. The last bit is a 'Don't care' value (R/W bit). Only one device must acknowledge this byte (the one that has the I<sup>2</sup>C-bus slave address).
  5. The CY15B256J sends an ACK.
  6. The master sends a Re-START command.
  7. The master sends Reserved Slave ID 0xF9.
  8. The CY15B256J sends an ACK.
  9. The Device ID Read can be done, starting with the 12 manufacturer bits, followed by the 9 part identification bits, and then the 3 die revision bits.
  10. The master ends the Device ID read sequence by NACKing the last byte, thus resetting the slave device state machine and allowing the master to send the STOP command.
- Note** The reading of the Device ID can be stopped anytime by sending a NACK command.

**Table 1. Device ID**

| Device ID<br>(3 bytes) | Device ID Description |                  |                 |                 |
|------------------------|-----------------------|------------------|-----------------|-----------------|
|                        | 23–12<br>(12 bits)    | 11–8<br>(4 bits) | 7–3<br>(5 bits) | 2–0<br>(3 bits) |
|                        | Manufacturer ID       | Product ID       |                 |                 |
|                        |                       | Density          | Variation       | Die Rev         |
| 004231h                | 000000000100          | 0010             | 00110           | 001             |

**Note** Product ID bits 0 and 4 are reserved.

**Figure 16. Read Device ID**



## Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. These user guidelines are not tested.

Storage temperature ..... -65 °C to +150 °C

Maximum accumulated storage time

At 150 °C ambient temperature ..... 1000 h

At 125 °C ambient temperature ..... 11000 h

At 85 °C ambient temperature ..... 121 Years

Ambient temperature

with power applied ..... -55 °C to +125 °C

Supply voltage on  $V_{DD}$  relative to  $V_{SS}$  ..... -1.0 V to +4.5 V

Input voltage\* ..... -1.0 V to +4.5 V and  $V_{IN} < V_{DD} + 1.0$  V

DC voltage applied to outputs

in HI-Z state ..... -0.5 V to  $V_{DD} + 0.5$  V

Transient voltage (< 20 ns)

on any pin to ground potential ..... -2.0 V to  $V_{DD} + 2.0$  V

Package power dissipation capability

( $T_A = 25$  °C) ..... 1.0 W

Surface mount lead soldering temperature

(3 seconds) ..... +260 °C

Electrostatic discharge voltage

Human Body Model (JEDEC Std JESD22-A114-B) ..... 2 kV

Charged Device Model (JEDEC Std JESD22-C101-A) ..... 500 V

Latch-up current ..... > 140 mA

\* Exception: The " $V_{IN} < V_{DD} + 1.0$  V" restriction does not apply to the SCL and SDA inputs.

## Operating Range

| Range        | Ambient Temperature ( $T_A$ ) | $V_{DD}$       |
|--------------|-------------------------------|----------------|
| Automotive-E | -40 °C to +125 °C             | 2.0 V to 3.6 V |

## DC Electrical Characteristics

Over the [Operating Range](#)

| Parameter       | Description                                 | Test Conditions                                                                                 | Min                  | Typ <sup>[2]</sup> | Max                  | Unit |
|-----------------|---------------------------------------------|-------------------------------------------------------------------------------------------------|----------------------|--------------------|----------------------|------|
| $V_{DD}$        | Power supply                                |                                                                                                 | 2.0                  | 3.3                | 3.6                  | V    |
| $I_{DD}$        | Average $V_{DD}$ current                    | SCL toggling between $V_{DD} - 0.2$ V and $V_{SS}$ , other inputs $V_{SS}$ or $V_{DD} - 0.2$ V. | $f_{SCL} = 100$ kHz  | —                  | 500                  | μA   |
|                 |                                             |                                                                                                 | $f_{SCL} = 1$ MHz    | —                  | 500                  | μA   |
|                 |                                             |                                                                                                 | $f_{SCL} = 3.4$ MHz  | —                  | 1000                 | μA   |
| $I_{SB}$        | $V_{DD}$ standby current                    | SCL = SDA = $V_{DD}$ . All other inputs $V_{SS}$ or $V_{DD}$ . Stop command issued.             | —                    | —                  | 500                  | μA   |
| $I_{ZZ}$        | Sleep mode current                          | SCL = SDA = $V_{DD}$ . All other inputs $V_{SS}$ or $V_{DD}$ . Stop command issued.             | —                    | —                  | 12                   | μA   |
| $I_{LI}$        | Input leakage current (Except WP and A2–A0) | $V_{SS} \leq V_{IN} \leq V_{DD}$                                                                | -1                   | —                  | +1                   | μA   |
|                 | Input leakage current (for WP and A2–A0)    | $V_{SS} \leq V_{IN} \leq V_{DD}$                                                                | -1                   | —                  | +100                 | μA   |
| $I_{LO}$        | Output leakage current                      | $V_{SS} \leq V_{OUT} \leq V_{DD}$                                                               | -1                   | —                  | +1                   | μA   |
| $V_{IH}$        | Input HIGH voltage (SDL, SDA)               |                                                                                                 | $0.75 \times V_{DD}$ | —                  | $V_{DD(max)} + 0.3$  | V    |
|                 | Input HIGH voltage (WP, A2–A0)              |                                                                                                 | $0.75 \times V_{DD}$ | —                  | $V_{DD} + 0.3$       | V    |
| $V_{IL}$        | Input LOW voltage                           |                                                                                                 | -0.3                 | —                  | $0.25 \times V_{DD}$ | V    |
| $V_{OL}^{[3]}$  | Output LOW voltage                          | $I_{OL} = 3$ mA                                                                                 | —                    | —                  | 0.4                  | V    |
|                 |                                             | $I_{OL} = 6$ mA                                                                                 | —                    | —                  | 0.6                  | V    |
| $R_{in}^{[4]}$  | Input resistance (WP, A2–A0)                | For $V_{IN} = V_{IL(Max)}$                                                                      | 50                   | —                  | —                    | kΩ   |
|                 |                                             | For $V_{IN} = V_{IH(Min)}$                                                                      | 1                    | —                  | —                    | MΩ   |
| $V_{hys}^{[5]}$ | Hysteresis of Schmitt Trigger inputs        | $f_{SCL} = 100$ kHz, 400 kHz, 1 MHz                                                             | $0.05 \times V_{DD}$ | —                  | —                    | V    |
|                 |                                             | $f_{SCL} = 3.4$ MHz                                                                             | $0.06 \times V_{DD}$ | —                  | —                    | V    |

### Notes

2. Typical values are at 25 °C,  $V_{DD} = V_{DD(typ)}$ . Not 100% tested.

3. The CY15B256J does not meet the NXP I<sup>2</sup>C specification in the Fast-mode Plus (Fm+, 1 MHz) for  $I_{OL}$  of 20 mA at a  $V_{OL}$  of 0.4 V.

4. The input pull-down circuit is strong (50 kΩ) when the input voltage is below  $V_{IL}$  and weak (1 MΩ) when the input voltage is above  $V_{IH}$ .

5. The CY15B256J does not meet the NXP I<sup>2</sup>C specification in the High Speed Mode (Hs-mode, 3.4 MHz) for  $V_{hys}$  of  $0.1 \times V_{DD}$ .

## Data Retention and Endurance

| Parameter       | Description    | Test condition             | Min              | Max | Unit   |
|-----------------|----------------|----------------------------|------------------|-----|--------|
| T <sub>DR</sub> | Data retention | T <sub>A</sub> = 125 °C    | 11000            | –   | Hours  |
|                 |                | T <sub>A</sub> = 105 °C    | 11               | –   | Years  |
|                 |                | T <sub>A</sub> = 85 °C     | 121              | –   | Years  |
| NV <sub>C</sub> | Endurance      | Over Operating Temperature | 10 <sup>13</sup> | –   | Cycles |

## Example of an F-RAM Life Time in an AEC-Q100 Automotive Application

An application does not operate under a steady temperature for the entire usage life time of the application. Instead, it is often expected to operate in multiple temperature environments throughout the application's usage life time. Accordingly, the retention specification for F-RAM in applications often needs to be calculated cumulatively. An example calculation for a multi-temperature thermal profiles is given below.

| Temperature<br>T | Time Factor<br>t | Acceleration Factor with respect to Tmax<br>A [6]                                                | Profile Factor<br>P                                                                                  | Profile Life Time<br>L (P)      |
|------------------|------------------|--------------------------------------------------------------------------------------------------|------------------------------------------------------------------------------------------------------|---------------------------------|
|                  |                  | $A = \frac{L(T)}{L(T_{max})} = e^{\frac{E_a}{k} \left( \frac{1}{T} - \frac{1}{T_{max}} \right)}$ | $P = \frac{1}{\left( \frac{t_1}{A_1} + \frac{t_2}{A_2} + \frac{t_3}{A_3} + \frac{t_4}{A_4} \right)}$ | L(P) = P × L(T <sub>max</sub> ) |
| T1 = 125 °C      | t1 = 0.1         | A1 = 1                                                                                           | 8.33                                                                                                 | > 10.46 Years                   |
| T2 = 105 °C      | t2 = 0.15        | A2 = 8.67                                                                                        |                                                                                                      |                                 |
| T3 = 85 °C       | t3 = 0.25        | A3 = 95.68                                                                                       |                                                                                                      |                                 |
| T4 = 55 °C       | t4 = 0.50        | A4 = 6074.80                                                                                     |                                                                                                      |                                 |

## Capacitance

| Parameter [7]   | Description                        | Test Conditions                                                            | Max | Unit |
|-----------------|------------------------------------|----------------------------------------------------------------------------|-----|------|
| C <sub>IO</sub> | Input/Output pin capacitance (SDA) | T <sub>A</sub> = 25 °C, f = 1 MHz, V <sub>DD</sub> = V <sub>DD</sub> (typ) | 8   | pF   |
| C <sub>I</sub>  | Input pin capacitance              |                                                                            | 6   | pF   |

## Thermal Resistance

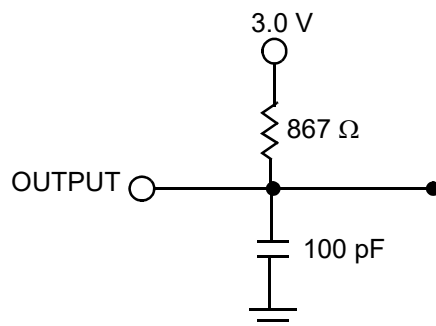
| Parameter [7]   | Description                              | Test Conditions                                                                                              | 8-pin SOIC | Unit |
|-----------------|------------------------------------------|--------------------------------------------------------------------------------------------------------------|------------|------|
| Θ <sub>JA</sub> | Thermal resistance (junction to ambient) | Test conditions follow standard test methods and procedures for measuring thermal impedance, per EIA/JESD51. | 146        | °C/W |
| Θ <sub>JC</sub> | Thermal resistance (junction to case)    |                                                                                                              | 48         | °C/W |

### Notes

- Where k is the Boltzmann constant 8.617 × 10<sup>-5</sup> eV/K, T<sub>max</sub> is the highest temperature specified for the product, and T is any temperature within the F-RAM product specification. All temperatures are in Kelvin in the equation.
- This parameter is periodically sampled and not 100% tested.

## AC Test Loads and Waveforms

Figure 17. AC Test Loads and Waveforms



## AC Test Conditions

Input pulse levels ..... 10% and 90% of  $V_{DD}$

Input rise and fall times ..... 10 ns

Input and output timing reference levels .....  $0.5 \times V_{DD}$

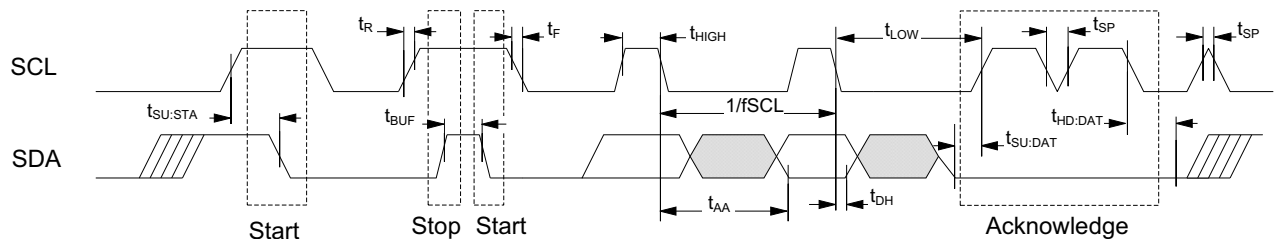
Output load capacitance ..... 100 pF

## AC Switching Characteristics

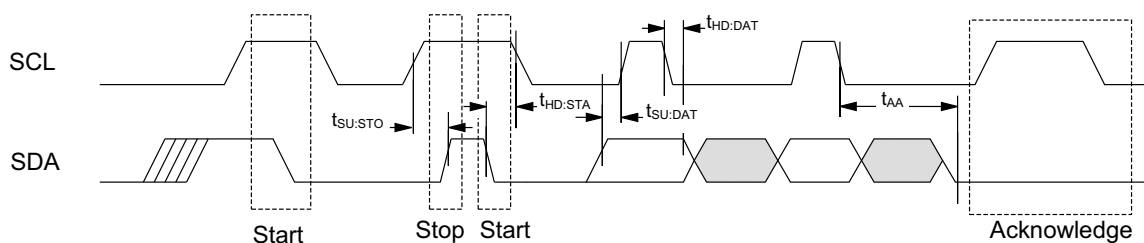
Over the [Operating Range](#)

| Parameters <sup>[8]</sup>       |                      | Description                                                      | Fast-mode Plus (Fm+) <sup>[10]</sup> |     | Hs-mode <sup>[10]</sup> |     | Unit |
|---------------------------------|----------------------|------------------------------------------------------------------|--------------------------------------|-----|-------------------------|-----|------|
| Cypress Parameter               | Alt. Parameter       |                                                                  | Min                                  | Max | Min                     | Max |      |
| f <sub>SCL</sub> <sup>[9]</sup> |                      | SCL clock frequency                                              | –                                    | 1.0 | –                       | 3.4 | MHz  |
| t <sub>SU;STA</sub>             |                      | Start condition setup for repeated Start                         | 260                                  | –   | 160                     | –   | ns   |
| t <sub>HD;STA</sub>             |                      | Start condition hold time                                        | 260                                  | –   | 160                     | –   | ns   |
| t <sub>LOW</sub>                |                      | Clock LOW period                                                 | 500                                  | –   | 160                     | –   | ns   |
| t <sub>HIGH</sub>               |                      | Clock HIGH period                                                | 260                                  | –   | 60                      | –   | ns   |
| t <sub>SU;DAT</sub>             | t <sub>SU;DATA</sub> | Data in setup                                                    | 50                                   | –   | 10                      | –   | ns   |
| t <sub>HD;DAT</sub>             | t <sub>HD;DATA</sub> | Data in hold                                                     | 0                                    | –   | 0                       | 70  | ns   |
| t <sub>DH</sub>                 |                      | Data output hold (from SCL at V <sub>IL</sub> )                  | 0                                    | –   | 0                       | –   | ns   |
| t <sub>R</sub> <sup>[11]</sup>  | t <sub>r</sub>       | Input rise time                                                  | –                                    | 120 | 10                      | 80  | ns   |
| t <sub>F</sub> <sup>[11]</sup>  | t <sub>f</sub>       | Input fall time                                                  | 20 × (V <sub>DD</sub> / 5.5 V)       | 120 | 10                      | 80  | ns   |
| t <sub>SU;STO</sub>             |                      | STOP condition setup                                             | 260                                  | –   | 160                     | –   | ns   |
| t <sub>AA</sub>                 | t <sub>VD;DATA</sub> | SCL LOW to SDA Data Out Valid                                    | –                                    | 450 | –                       | 130 | ns   |
| t <sub>VD;ACK</sub>             |                      | ACK output valid time                                            | –                                    | 450 | –                       | 130 | ns   |
| t <sub>OF</sub> <sup>[11]</sup> |                      | Output fall time from V <sub>IH</sub> min to V <sub>IL</sub> max | 20 × (V <sub>DD</sub> /5.5 V)        | 120 | –                       | 80  | ns   |
| t <sub>BUF</sub>                |                      | Bus free before new transmission                                 | 500                                  | –   | 300                     | –   | ns   |
| t <sub>SP</sub>                 |                      | Noise suppression time constant on SCL, SDA                      | 0                                    | 50  | –                       | 5   | ns   |

**Figure 18. Read Bus Timing Diagram**



**Figure 19. Write Bus Timing Diagram**



### Notes

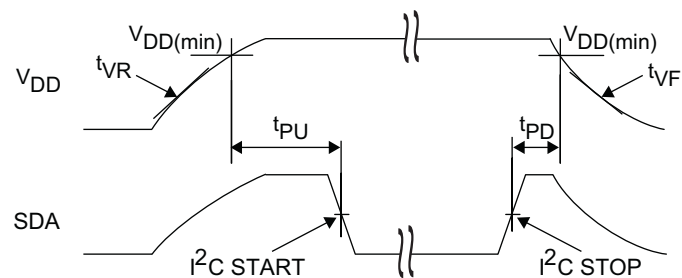
8. Test conditions assume signal transition time of 10 ns or less, timing reference levels of V<sub>DD</sub>/2, input pulse levels of 0 to V<sub>DD</sub>(typ), and output loading of the specified I<sub>OL</sub> and 100 pF load capacitance shown in [Figure 17](#).
9. The speed-related specifications are guaranteed characteristic points along a continuous curve of operation from DC to f<sub>SCL</sub> (max).
10. Bus Load (Cb) considerations; Cb < 550 pF for I<sup>2</sup>C clock frequency (SCL) 1 MHz; Cb < 100 pF for SCL at 3.4 MHz.
11. These parameters are guaranteed by design and are not tested.

## Power Cycle Timing

Over the [Operating Range](#)

| Parameter           | Description                                                         | Min | Max | Unit            |
|---------------------|---------------------------------------------------------------------|-----|-----|-----------------|
| $t_{PU}$            | Power-up $V_{DD}(\text{min})$ to first access (START condition)     | 250 | –   | $\mu\text{s}$   |
| $t_{PD}$            | Last access (STOP condition) to power-down ( $V_{DD}(\text{min})$ ) | 0   | –   | $\mu\text{s}$   |
| $t_{VR}^{[12, 13]}$ | $V_{DD}$ power-up ramp rate                                         | 50  | –   | $\mu\text{s/V}$ |
| $t_{VF}^{[12, 13]}$ | $V_{DD}$ power-down ramp rate                                       | 100 | –   | $\mu\text{s/V}$ |
| $t_{REC}$           | Recovery time from sleep mode                                       | –   | 400 | $\mu\text{s}$   |

**Figure 20. Power Cycle Timing**



### Notes

12. Slope measured at any point on the  $V_{DD}$  waveform.
13. These parameters are guaranteed by design and are not tested.

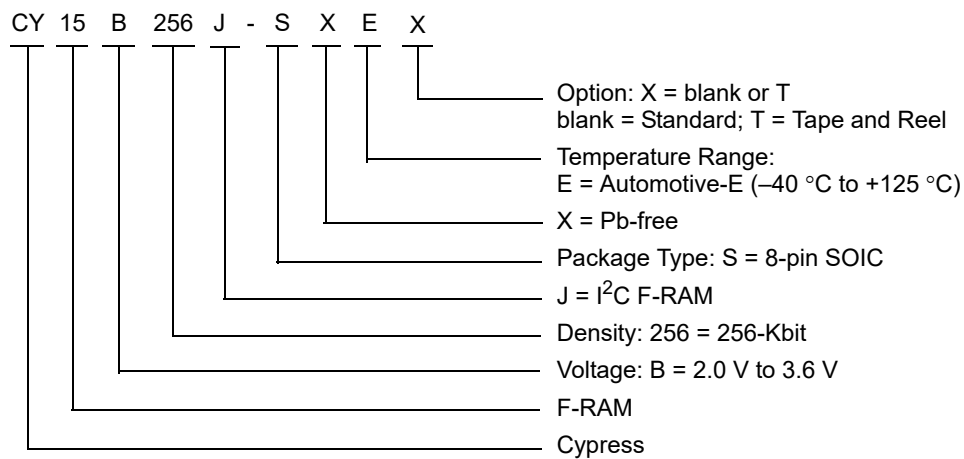


## Ordering Information

| Ordering Code  | Package Diagram | Package Type | Operating Range |
|----------------|-----------------|--------------|-----------------|
| CY15B256J-SXE  | 51-85066        | 8-pin SOIC   | Automotive-E    |
| CY15B256J-SXET | 51-85066        | 8-pin SOIC   |                 |

All these parts are Pb-free. Contact your local Cypress sales representative for availability of these parts.

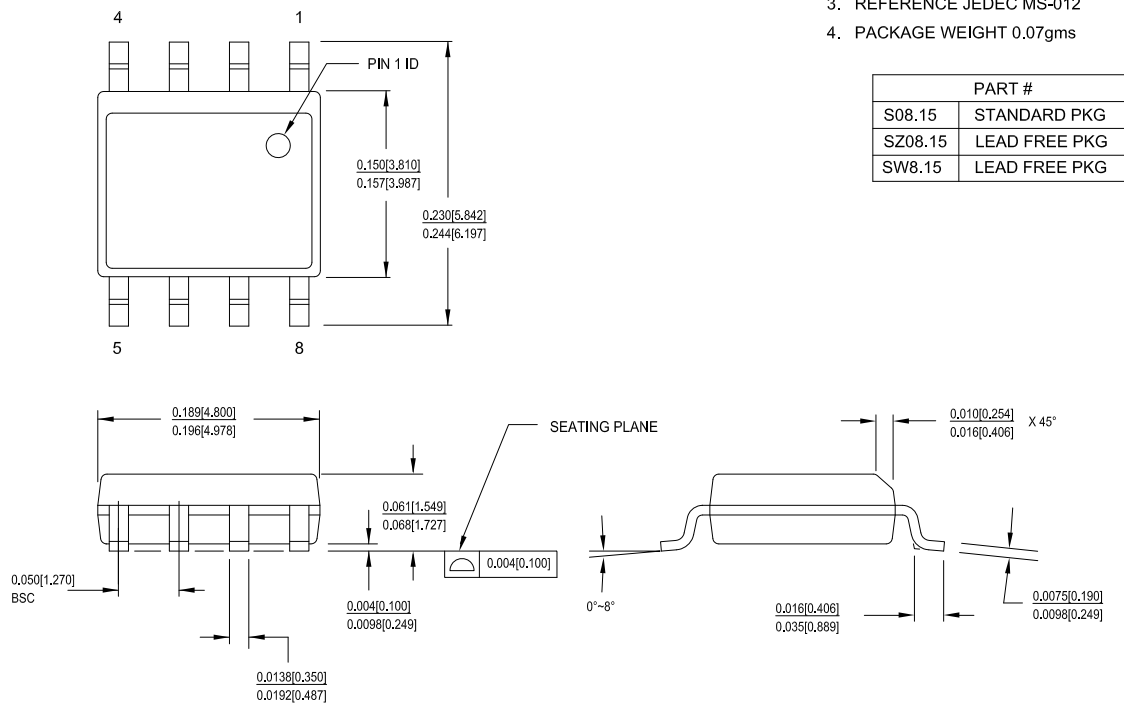
## Ordering Code Definitions



## Package Diagram

**Figure 21. 8-pin SOIC (150 Mils) Package Outline, 51-85066**

1. DIMENSIONS IN INCHES[MM] MIN.  
MAX.
2. PIN 1 ID IS OPTIONAL,  
ROUND ON SINGLE LEADFRAME  
RECTANGULAR ON MATRIX LEADFRAME
3. REFERENCE JEDEC MS-012
4. PACKAGE WEIGHT 0.07gms



51-85066 \*I

## Acronyms

| Acronym          | Description                                |
|------------------|--------------------------------------------|
| ACK              | acknowledge                                |
| CMOS             | complementary metal oxide semiconductor    |
| EIA              | Electronic Industries Alliance             |
| I <sup>2</sup> C | inter-integrated circuit                   |
| I/O              | input/output                               |
| JEDEC            | Joint Electron Devices Engineering Council |
| LSB              | least significant bit                      |
| MSB              | most significant bit                       |
| NACK             | no acknowledge                             |
| RoHS             | Restriction of Hazardous Substances        |
| R/W              | read/write                                 |
| SCL              | serial clock line                          |
| SDA              | serial data access                         |
| SOIC             | small outline integrated circuit           |
| WP               | write protect                              |

## Document Conventions

### Units of Measure

| Symbol | Unit of Measure |
|--------|-----------------|
| °C     | Degrees Celsius |
| Hz     | hertz           |
| Kb     | 1024 bits       |
| kHz    | kilohertz       |
| kΩ     | kilohms         |
| MHz    | megahertz       |
| MΩ     | megaohms        |
| μA     | microamperes    |
| μs     | microseconds    |
| mA     | milliamperes    |
| ms     | milliseconds    |
| ns     | nanoseconds     |
| Ω      | ohms            |
| %      | percent         |
| pF     | picofarads      |
| V      | volts           |
| W      | watts           |

## Document History Page

| Document Title: CY15B256J, 256-Kbit (32K × 8) Automotive-E Serial (I <sup>2</sup> C) F-RAM<br>Document Number: 002-10968 |         |                 |                 |                                                                                                                                                                                                                |
|--------------------------------------------------------------------------------------------------------------------------|---------|-----------------|-----------------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| Rev.                                                                                                                     | ECN No. | Orig. of Change | Submission Date | Description of Change                                                                                                                                                                                          |
| **                                                                                                                       | 5120369 | GVCH            | 02/02/2016      | New data sheet.                                                                                                                                                                                                |
| *A                                                                                                                       | 5452636 | ZSK             | 09/28/2016      | Updated <a href="#">Power Cycle Timing</a> :<br>Changed minimum value of t <sub>PU</sub> parameter from 1 ms to 250 μs.<br>Updated to new template.                                                            |
| *B                                                                                                                       | 6177965 | ZSK             | 05/17/2018      | Changed status from Advance to Final.<br>Updated <a href="#">Package Diagram</a> :<br>spec 51-85066 – Changed revision from *H to *I.<br>Updated to new template.                                              |
| *C                                                                                                                       | 6393564 | GVCH            | 11/26/2018      | Updated <a href="#">Maximum Ratings</a> :<br>Replaced “–55 °C to +150 °C” with “–65 °C to +150 °C” in ratings corresponding to “Storage temperature”.<br>Updated to new template.<br>Completing Sunset Review. |

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